Quad buffers; 3-State Rev. 4 — 23 January 2013

Product data sheet

1. **General description**

The 74F126 provides four non-inverting buffer/line drivers with 3-state outputs. The 3-state outputs (nY) are controlled by the output enable input (nOE). A LOW at nOE causes the outputs to assume a high-impedance OFF-state.

Features and benefits 2.

High impedance NPN base inputs for reduced loading (20 μA in HIGH and LOW states)

Ordering information 3.

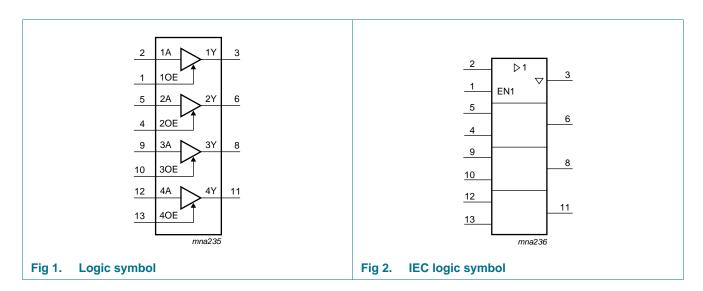
Table 1. **Ordering information**

Type number	Package			
	Temperature range	Name	Description	Version
N74F126N	0 °C to +70 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1
N74F126D	0 °C to +70 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1



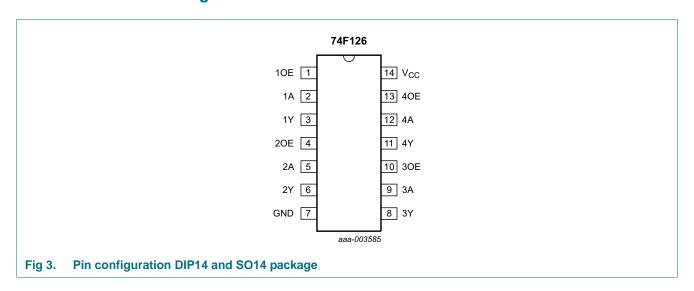
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4. Functional diagram



5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description

Pin	Description	Unit load HIGH/LOW	Load value ^[1] HIGH/LOW
1, 4, 10, 13	output enable input (active HIGH)	1.0/0.033	20 μΑ/20 μΑ
2, 5, 9, 12	data input	1.0/0.033	20 μΑ/20 μΑ
3, 6, 8, 11	data output	750/106.7	15 mA/64 mA
7	ground (0 V)	-	-
14	supply voltage	-	-
	1, 4, 10, 13 2, 5, 9, 12 3, 6, 8, 11 7	1, 4, 10, 13 output enable input (active HIGH) 2, 5, 9, 12 data input 3, 6, 8, 11 data output 7 ground (0 V)	HIGH/LOW 1, 4, 10, 13 output enable input (active HIGH) 1.0/0.033 2, 5, 9, 12 data input 1.0/0.033 3, 6, 8, 11 data output 750/106.7 7 ground (0 V) -

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[1] One FAST Unit Load (UL) is defined as 20 μA in HIGH state, 0.6 μA in LOW state.

6. Functional description

Table 3. Function table[1]

Control	Input	Output
nOE	nA	nY
Н	L	L
	Н	Н
L	X	Z

^[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
Vo	output voltage	output in HIGH-state	<u>[1]</u> –0.5	V_{CC}	V
I _{IK}	input clamping current	V _I < 0 V	-30	+5	mA
Io	output current	output in LOW-state	-	128	mA
T _{amb}	ambient temperature	in free air	<u>[2]</u> 0	70	°C
T _{stg}	storage temperature		-65	+150	°C

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CC}	supply voltage		4.5	5.0	5.5	V
V _{IH}	HIGH-level input voltage		2.0	-	-	V
V _{IL}	LOW-level input voltage		-	-	0.8	V
I _{IK}	input clamping current		-18	-	-	mA
I _{OH}	HIGH-level output current		-15	-	-	mA
I _{OL}	LOW-level output current		-	-	64	mA
T _{amb}	ambient temperature		0		70	°C

^[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

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9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions			25 °C		0 °C to	+70 °C	Unit
			N	/lin	Typ[1]	Max	Min	Max	
V_{IK}	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$	_	1.2	-0.73	-	-1.2	-	V
V_{OH}	HIGH-level output	$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$							
	voltage	$I_{OH} = -3 \text{ mA}$							
		V _{CC} = ±10 %		-	-	-	2.4	-	V
		V _{CC} = ±5 %		-	3.3	-	2.7	-	V
		$I_{OH} = -15 \text{ mA}$							
		V _{CC} = ±10 %		-	-	-	2.0	-	V
V_{OL}	LOW-level output	$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$							
	voltage	I _{OL} = 64 mA							
		V _{CC} = ±10 %		-	-	-	-	0.55	V
		V _{CC} = ±5 %		-	0.42	-	-	0.55	V
I _I	input leakage current	$V_{CC} = 0 \text{ V}; V_I = 7.0 \text{ V}$		-	-	-	-	100	μΑ
I _{IH}	HIGH-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 2.7 \text{ V}$		-	-	-	-	20	μΑ
I _{IL}	LOW-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 0.5 \text{ V}$		-	-	-	-20	-	μΑ
I _{OZ}	OFF-state output current	$V_{CC} = 5.5 \text{ V}$							
		$V_0 = 2.7 \text{ V}$		-	-	-	-	50	μΑ
		$V_0 = 0.5 \text{ V}$		-	-	-	-50	-	μΑ
Io	output current	V _{CC} = 5.5 V	[2]	-	-	-	-225	-100	mΑ
I _{CC}	supply current	$V_{CC} = 5.5 \text{ V}; V_I = \text{GND or } V_{CC}$							
		outputs HIGH-state		-	20	-	-	30	mΑ
		outputs LOW-state		-	32	-	-	48	mΑ
		outputs OFF-state		-	26	-	-	39	mΑ

^[1] All typical values are measured at $V_{CC} = 5 \text{ V}$.

10. Dynamic characteristics

Table 7. Dynamic characteristics $GND = 0 \ V.$ Test circuit is shown in Figure 6.

Symbol	Parameter	Conditions	25 °C;	V _{CC} =	5.0 V	0 °C to +7 V _{CC} = 5.0	Unit	
			Min	Тур	Max	Min	Max	
t _{PLH}	LOW to HIGH propagation delay	nA to nY, see Figure 4	2.0	4.0	6.5	2.0	7.0	ns
t _{PHL}	HIGH to LOW propagation delay	nA to nY; see Figure 4	3.0	5.5	8.0	3.0	8.5	ns
t _{PZH}	OFF-state to HIGH propagation delay	nOE to nY; see Figure 5	4.0	6.0	7.5	3.5	8.5	ns

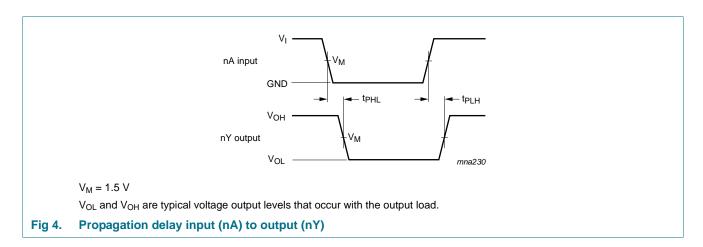
^[2] No more than one output should be tested at a time, and the duration of the test should not exceed one second.

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Table 7. Dynamic characteristics ...continued GND = 0 V. Test circuit is shown in <u>Figure 6</u>.

Symbol	Parameter	Conditions 25 °C; $V_{CC} = 5.0 \text{ V}$		0 °C to +7 V _{CC} = 5.0	Unit			
			Min	Тур	Max	Min	Max	
t_{PZL}	OFF-state to LOW propagation delay	nOE to nY; see Figure 5	4.0	6.0	8.0	3.5	8.5	ns
t _{PHZ}	HIGH to OFF-state propagation delay	nOE to nY; see Figure 5	2.0	4.5	6.5	2.0	7.5	ns
t _{PLZ}	LOW to OFF-state propagation delay	nOE to nY; see Figure 5	3.0	5.5	7.5	3.0	8.0	ns

11. Waveforms



nOE input V_{M} GND – tpLZ → tpzL V_{CC} output LOW-to-OFF OFF-to-LOW V_{OL} – tphz – ← t_{PZH} → V_{OH} output HIGH-to-OFF OFF-to-HIGH GND

outputs

 $V_{M} = 1.5 V$

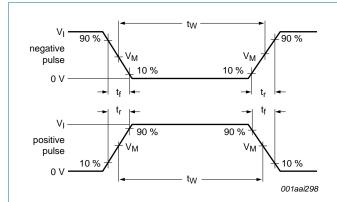
 V_{OL} and V_{OH} are typical voltage output levels that occur with the output load.

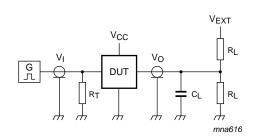
Fig 5. Enable and disable times

outputs disabled outputs

mna684

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b. Test circuit

a. Input pulse definition

Test data is given in Table 8.

Test circuit definitions:

 R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

V_{EXT} = Test voltage for switching times.

Fig 6. Load circuitry for switching times

Table 8. Test data

Input		Load		V _{EXT}				
V_{I}	f _i	t _W	t _r , t _f	C _L	R _L	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t _{PZL} , t _{PLZ}
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500Ω	open	open	7.0 V

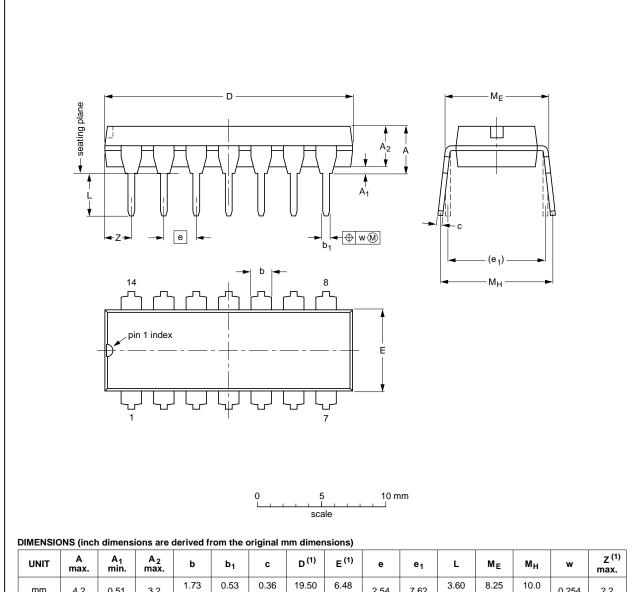
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12. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



	•					•									
UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E (1)	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

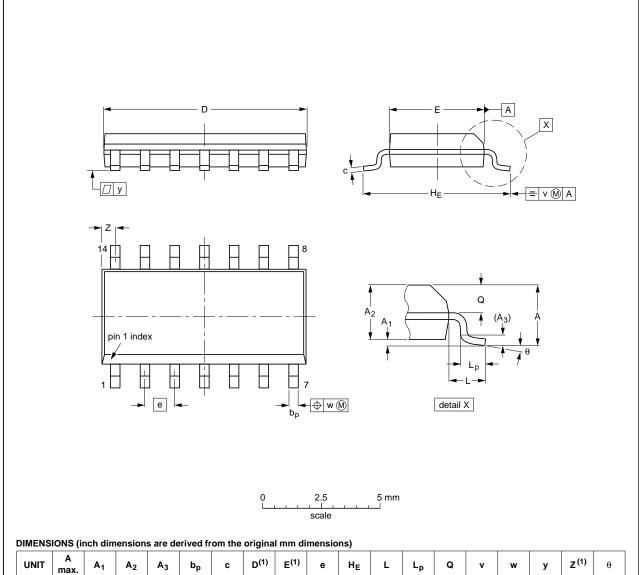
OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	/ERSION IEC JEDEC JEITA		PROJECTION	ISSUE DATE	
SOT27-1	050G04	MO-001	SC-501-14		99-12-27 03-02-13

Fig 7. Package outline SOT27-1 (DIP14)

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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01	1	0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012				99-12-27 03-02-19

Fig 8. Package outline SOT108-1 (SO14)

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13. Abbreviations

Table 9. Abbreviations

Acronym	Description	
CMOS	Complementary Metal Oxide Semiconductor	
LSTTL	Low-power Schottky Transistor-Transistor Logic	
ESD	ElectroStatic Discharge	
НВМ	Human Body Model	
MM	Machine Model	
CDM	Charge-Device Model	
TTL	Transistor-Transistor Logic	

14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74F126 v.4	20130123	Product data sheet	-	74F126 v.3
Modifications:	 Features and 	d benefits: Changed mA into	μA (errata).	
74F126 v.3	20130118	Product data sheet	-	74F126 v.2
Modifications:		f this data sheet has been re NXP Semiconductors.	edesigned to comply w	vith the new identity
	 Legal texts h 	ave been adapted to the ne	w company name whe	re appropriate.
74F126 v.2	19890328	Product data sheet	-	74F126 v.1

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15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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